IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Hans Meiling et al.

Filed:

August 5, 1999

Title of Invention:

SEMICONDUCTING DEVICES AND METHOD

OF MAKING THEREOF

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I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" Service under 37 CFR 1.10 on the date indicated above and is addressed to the Assistant Commissioner for Datents Washington D. C. 2031

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INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents Box PATENT APPLICATION Washington, D.C. 20231

Sir:

Applicants bring to the attention of the Examiner the prior art cited in the parent application, serial no. 09/331,528. Also enclosed is a copy of Form PTO-1449.

REMARKS

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP Attorneys for Applicants

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Sheet 1 of 1

Based on Form PTO-1449 ATTY. DOCKET NO. SERIAL NO. (3/90) 452080-2010 09/331,528 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Hans Meiling et al. (Use several sheets if necessary) FILING DATE August 5, 1999 GROUP 2814

	· -		U.S	S. PATENT DOCUMENTS			- j 1
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLAS S	FILING DATE APPROPRIATE
	AA	4,634,605	01/6/1987	Wiesman			
	AB	4,485,128	11/24/84	Dala et al.			
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_	AE	5,500,047	3/19/96	Park et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	0 687 753	12/20/95	Europe			
	АМ	43 33 416	4/6/95	Germany			
	AN						
	AO						
	AP						

	OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
AQ	Meiling H. et "Stability of hot-wire deposited amorphous-silicon thin-film transistors". Applied Physics Letters. 19 August 1996. AIP. USA. vol. 69. no. 8. ISSN 0003-6951. pages 1062-1064. XP000626137	
AR	Kikuo Ono et al., "Inverse-Staggered Polycrystalline Silicon thin Film Transistors Favricated By Excimer Laser Irradiation", Electronics & vol. 76, no. 12, December, 1993, pages 40-46, XP000468568	
AS	Doyle R. et al., "Production of high-quality amorphous silicon films by evaporative silane surface decomposition", Journal of Applied Physics, 15 Sept. 1988, USA, vol. 64, no. 6, ISSN 0021-8979, pages 3215-3223, XP000097188	
AT	Japanese Abstract of 01-162769. dated June 27. 1989: Araki Makoto: FORMATION OF AMORPHOUS SILICON	

EXAMINER		DATE CONSIDERED
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* EXAMINER:	Initial if reference considered, whether or not o	citation is in conformance with MDED 600 Drow Line

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.